

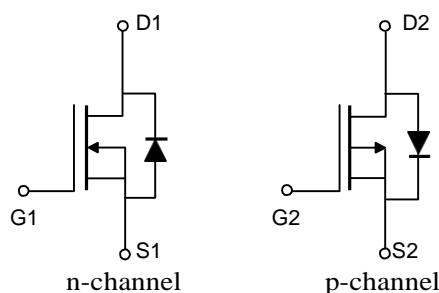
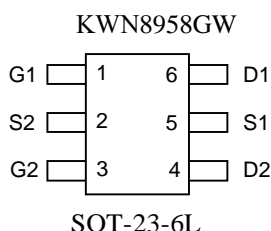
Complementary High Density Trench MOSFET

PRODUCT SUMMARY (N-Channel)

V _{DSS}	I _D	R _{DS(on)} (mΩ) Max
30V	4.5A	30 @ V _{GS} = 10V
	3.5A	44 @ V _{GS} = 4.5V

PRODUCT SUMMARY (P-Channel)

V _{DSS}	I _D	R _{DS(on)} (mΩ) Max
-30V	-3.5A	70 @ V _{GS} = -10V
	-3.0A	95 @ V _{GS} = -4.5V



ABSOLUTE MAXIMUM RATINGS (T_A = 25 °C unless otherwise noted)

Parameter	Symbol	N-Channel	P-Channel	Unit
Drain-Source Voltage	V _{DS}	30	-30	V
Gate-Source Voltage	V _{GS}	± 20	± 20	V
Drain Current-Continuous ^a @ T _A = 25 °C -Pulse ^b	I _D	4.5	3.5	A
	I _{DM}	18	14	A
Drain-Source Diode Forward Current ^a	I _S	2.5	-1.9	A
Maximum Power Dissipation ^a	P _D	1.25		W
		0.75		
Operating Junction and Storage Temperature Range	T _J , T _{STG}	- 55 to 150		°C

THERMAL CHARACTERISTICS

Thermal Resistance, Junction-to-Ambient ^a	R _{thJA}	100	°C/W
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Note :

a. Surface Mounted on FR4 Board , t ≤ 5sec.

b. Pulse width limited by maximum junction temperature.

N-Channel ELECTRICAL CHARACTERISTICS (T_A = 25 °C unless otherwise noted)

Parameter	Symbol	Condition	Min	Typ ^c	Max	Unit
OFF CHARACTERISTICS						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} = 0V , I _D = 250uA	30			V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 24V , V _{GS} = 0V			1	uA
Gate-Body Leakage	I _{GSS}	V _{GS} = ±20V , V _{DS} = 0V			±100	nA
ON CHARACTERISTICS^b						
Gate Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250uA	1	1.5	3	V
Drain-Source On-State Resistance	R _{DSON}	V _{GS} = 10V , I _D = 4.5A		24	30	mΩ
		V _{GS} = 4.5V , I _D = 3.5A		35	44	
Forward Transconductance	g _{fs}	V _{DS} = 15V , I _D = 4.5A		8.3		S
DRAIN-SOURCE DIODE CHARACTERISTICS^b						
Diode Forward Voltage	V _{SD}	V _{GS} = 0V , I _S = 1.0A		0.76	1.0	V
DYNAMIC CHARACTERISTICS^c						
Input Capacitance	C _{ISS}	V _{DS} = 10V , V _{GS} = 0V f = 1.0MHz		402		pF
Output Capacitance	C _{OSS}			96		pF
Reverse Transfer Capacitance	C _{RSS}			73		pF
SWITCHING CHARACTERISTICS^c						
Turn-On Delay Time	t _{D(ON)}	V _{DD} = 15V , I _D = 1A V _{GEN} = 10V R _L = 15 ohm R _{GEN} = 6 ohm		8.0		ns
Rise Time	t _r			2.4		ns
Turn-Off Delay Time	t _{D(OFF)}			20.6		ns
Fall Time	t _f			3.8		ns
Total Gate Charge	Q _g	V _{DS} = 10V		8.4		nC
Gate-Source Charge	Q _{gs}	I _D = 1A		1.7		nC
Gate-Drain Charge	Q _{gd}	V _{GS} = 10V		1.3		nC

Note

b. Pulse Test Pulse width ≤ 300us , Duty Cycle ≤ 2% .

c. Guaranteed by design , not subject to production testing .

P-Channel ELECTRICAL CHARACTERISTICS (TA = 25 °C unless otherwise noted)

Parameter	Symbol	Condition	Min	Typ ^c	Max	Unit	
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} = 0V , I _D = -250uA	-30			V	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = -24V , V _{GS} = 0V			-1	uA	
Gate-Body Leakage	I _{GSS}	V _{GS} = ±20V , V _{DS} = 0V			±100	nA	
ON CHARACTERISTICS^b							
Gate Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = -250uA	-1	-1.4	-3	V	
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = -10V , I _D = -3.5A		56	70	mΩ	
		V _{GS} = -4.5V , I _D = -3.0A		73	95		
Forward Transconductance	g _{fs}	V _{DS} = -15V , I _D = -3.5A		10.2		S	
DRAIN-SOURCE DIODE CHARACTERISTICS^b							
Diode Forward Voltage	V _{SD}	V _{GS} = 0V , I _S = -1.9A		-0.85	-1.3	V	
DYNAMIC CHARACTERISTICS^c							
Input Capacitance	C _{ISS}	V _{DS} = -15V , V _{GS} = 0V f = 1.0MHz		490		pF	
Output Capacitance	C _{OSS}				66		pF
Reverse Transfer Capacitance	C _{RSS}				53		pF
SWITCHING CHARACTERISTICS^c							
Turn-On Delay Time	t _{D(ON)}	V _{DD} = -15V , I _D = -1A V _{GEN} = -10V R _L = 15 ohm R _{GEN} = 6 ohm		4.4		ns	
Rise Time	t _r				2.2		ns
Turn-Off Delay Time	t _{D(OFF)}				22		ns
Fall Time	t _f				4.2		ns
Total Gate Charge	Q _g	V _{DS} = -15V		10		nC	
Gate-Source Charge	Q _{gs}	I _D = -1A		1.5		nC	
Gate-Drain Charge	Q _{gd}	V _{GS} = -10V		1.4		nC	

Note :

b. Pulse Test : Pulse width ≤ 300us , Duty Cycle ≤ 2% .

c. Guaranteed by design , not subject to production testing .

N-Channel:

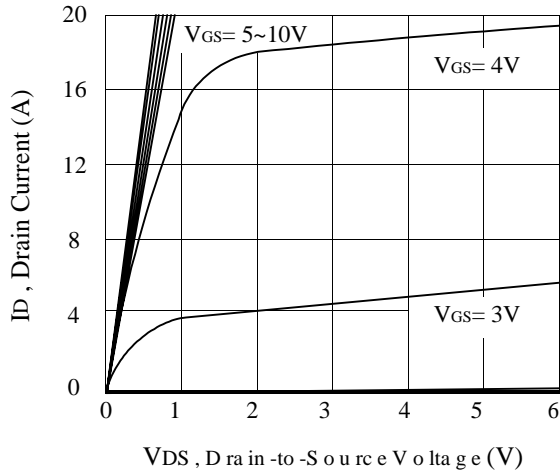


Figure 1. Output Characteristics

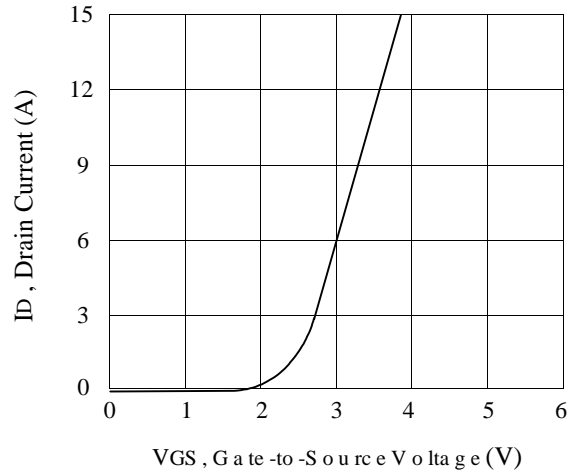


Figure 2. Transfer Characteristics

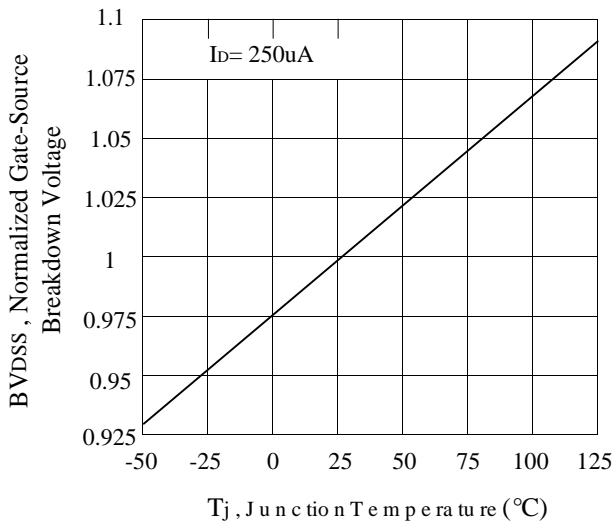


Figure 3. Breakdown Voltage Variation with Temperature

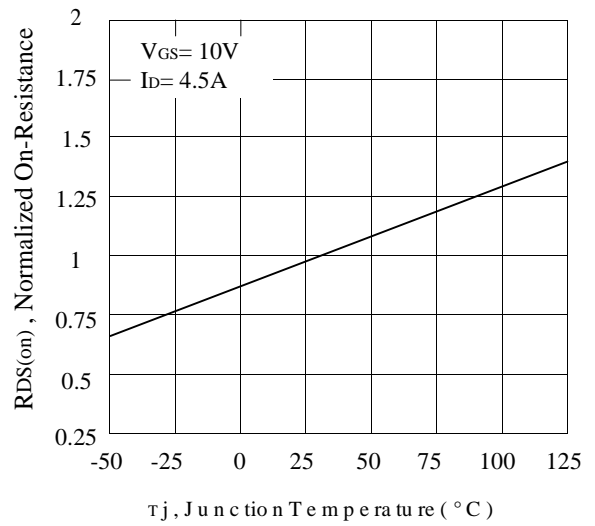


Figure 4. On-Resistance Variation with Temperature

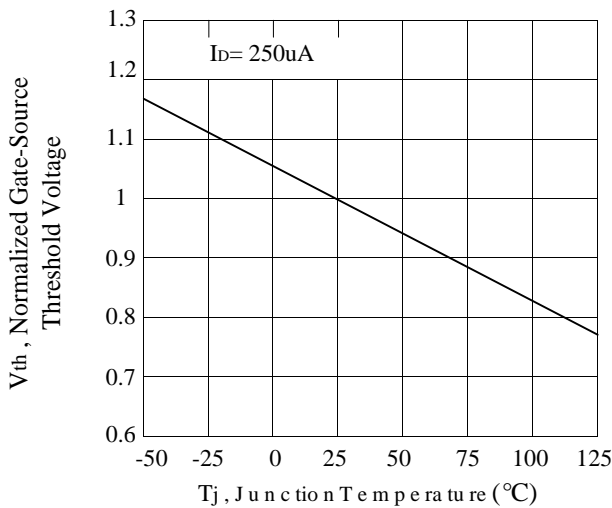


Figure 5. Gate Threshold Variation with Temperature

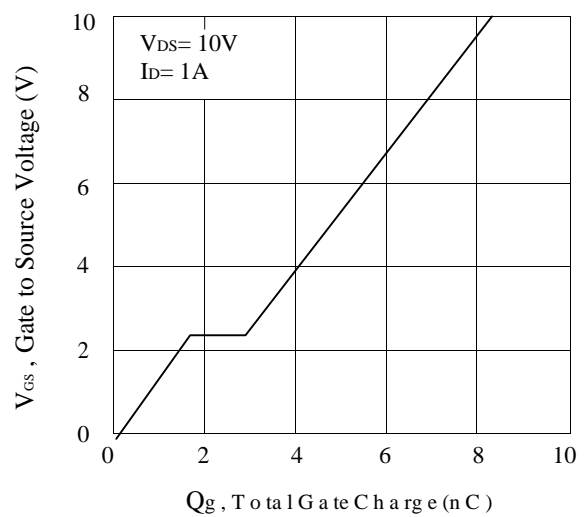
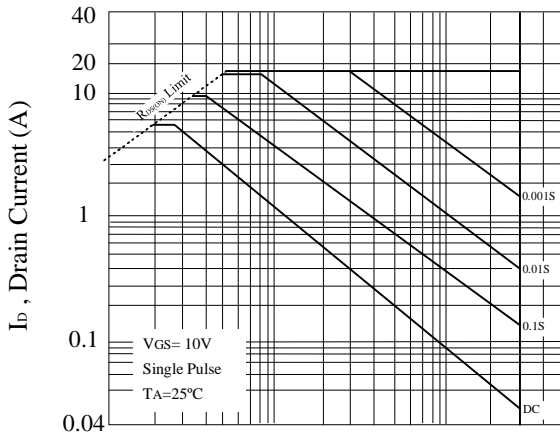
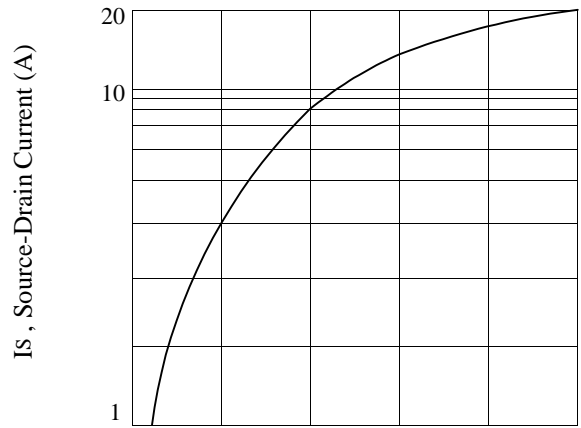


Figure 6. Gate Charge



VDS , Drain-Source Voltage (V)
 Figure 7. Maximum Safe Operating Area



VSD , Body Diode Forward Voltage (V)
 Figure 8. Body Diode Forward Voltage Variation with Source Current

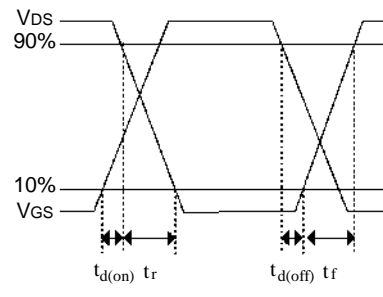
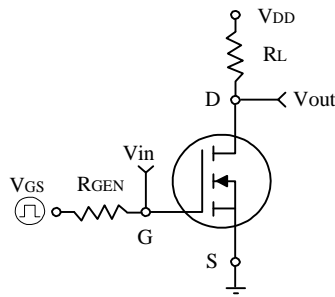


Figure 9. Switching Test Circuit and Switching Waveforms

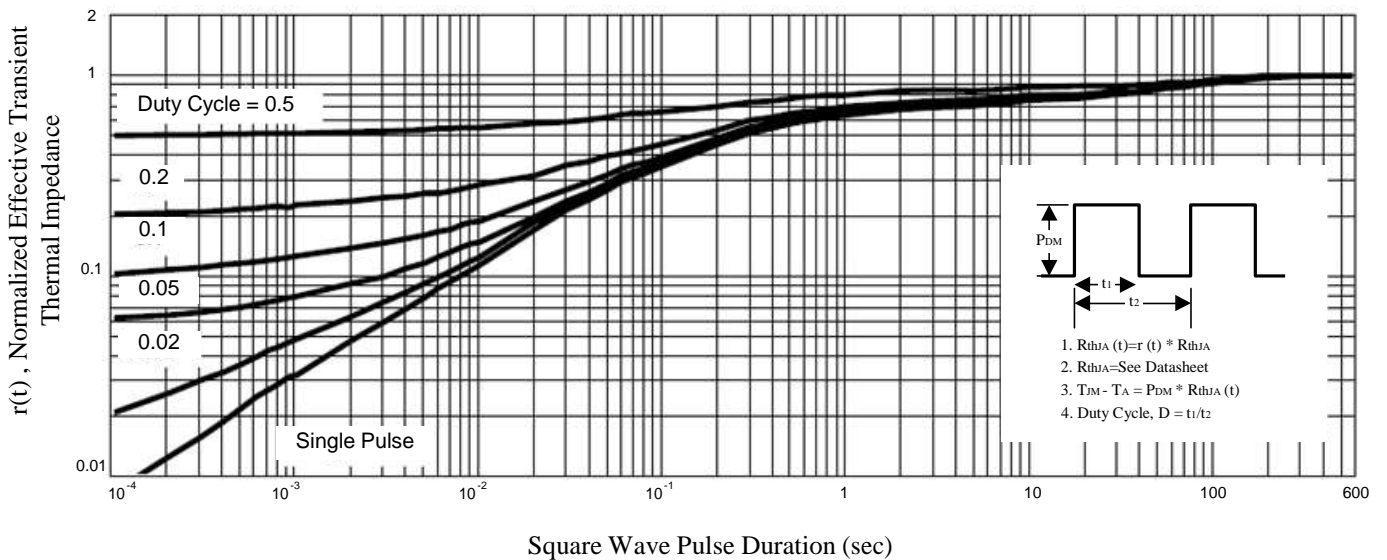


Figure 10. Normalized Thermal Transient Impedance Curve

P-Channel:

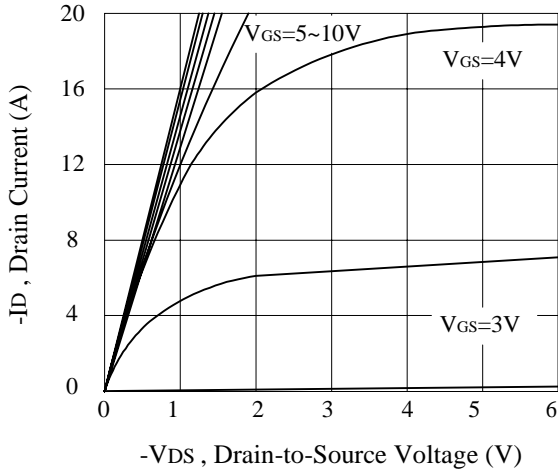


Figure 11. Output Characteristics

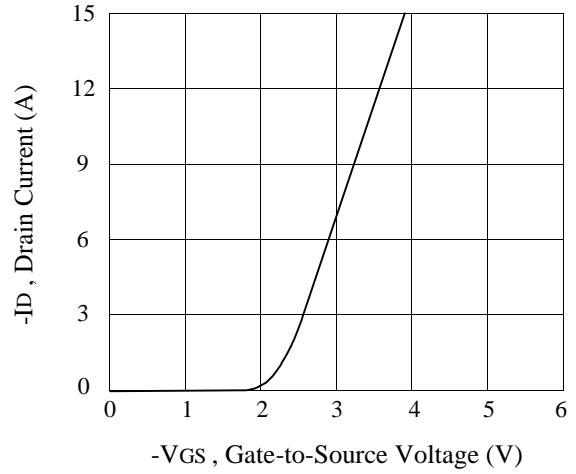


Figure 12. Transfer Characteristics

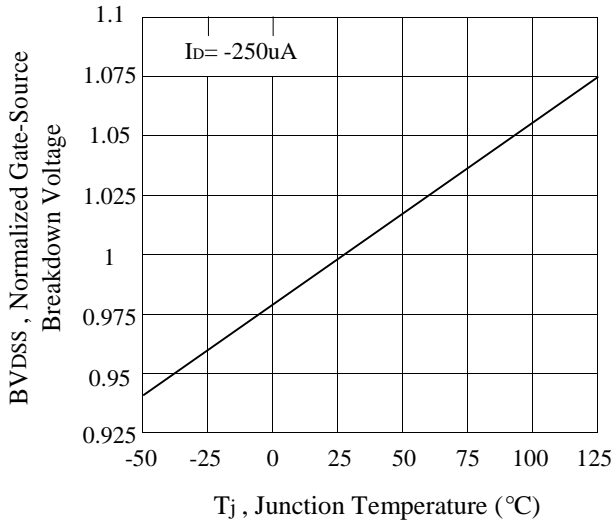


Figure 13. Breakdown Voltage Variation with Temperature

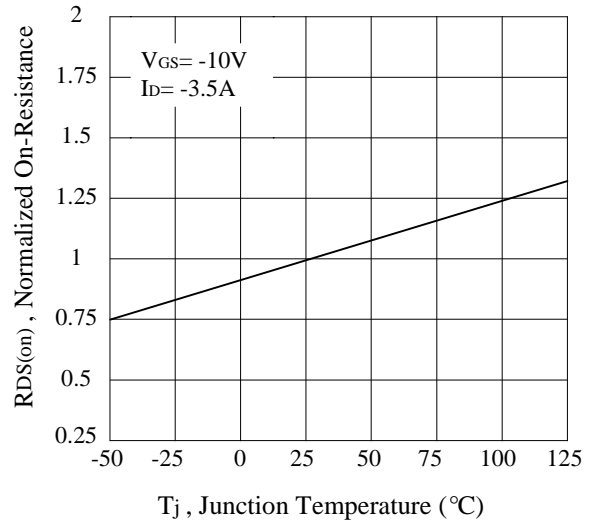


Figure 14. On-Resistance Variation with Temperature

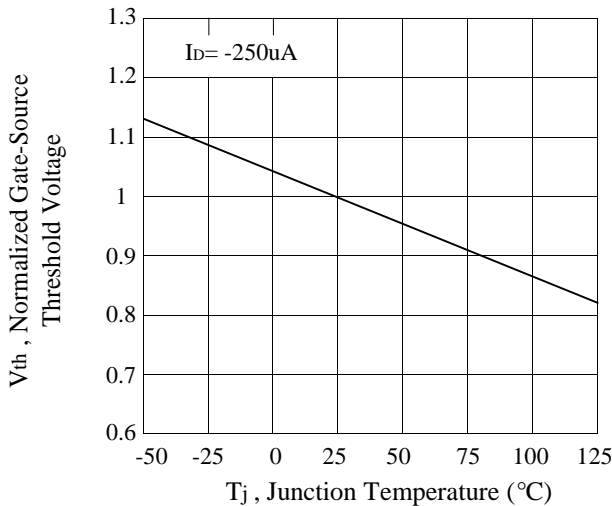


Figure 15. Gate Threshold Variation with Temperature

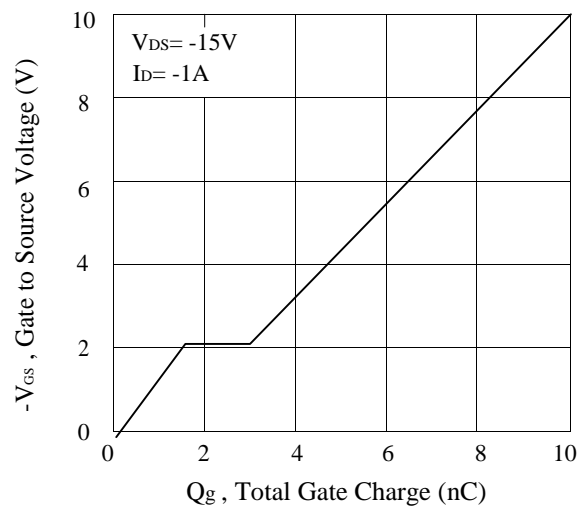
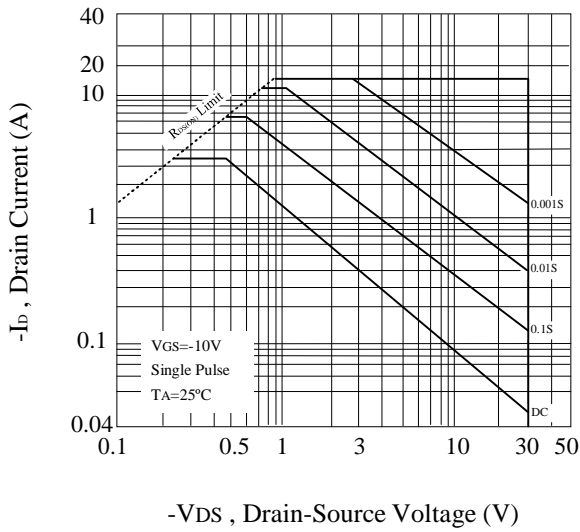
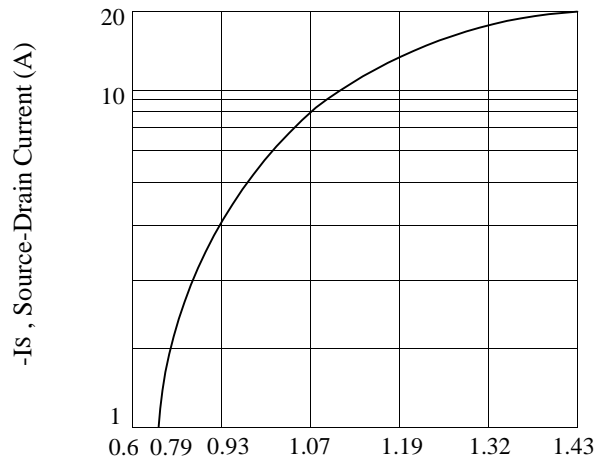


Figure 16. Gate Charge



-VDS , Drain-Source Voltage (V)
 Figure 17. Maximum Safe Operating Area



-VSD , Body Diode Forward Voltage (V)
 Figure 18. Body Diode Forward Voltage Variation with Source Current

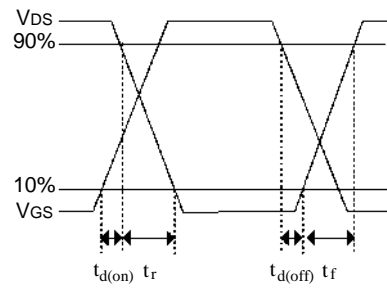
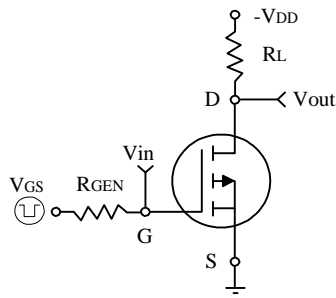


Figure 19. Switching Test Circuit and Switching Waveforms

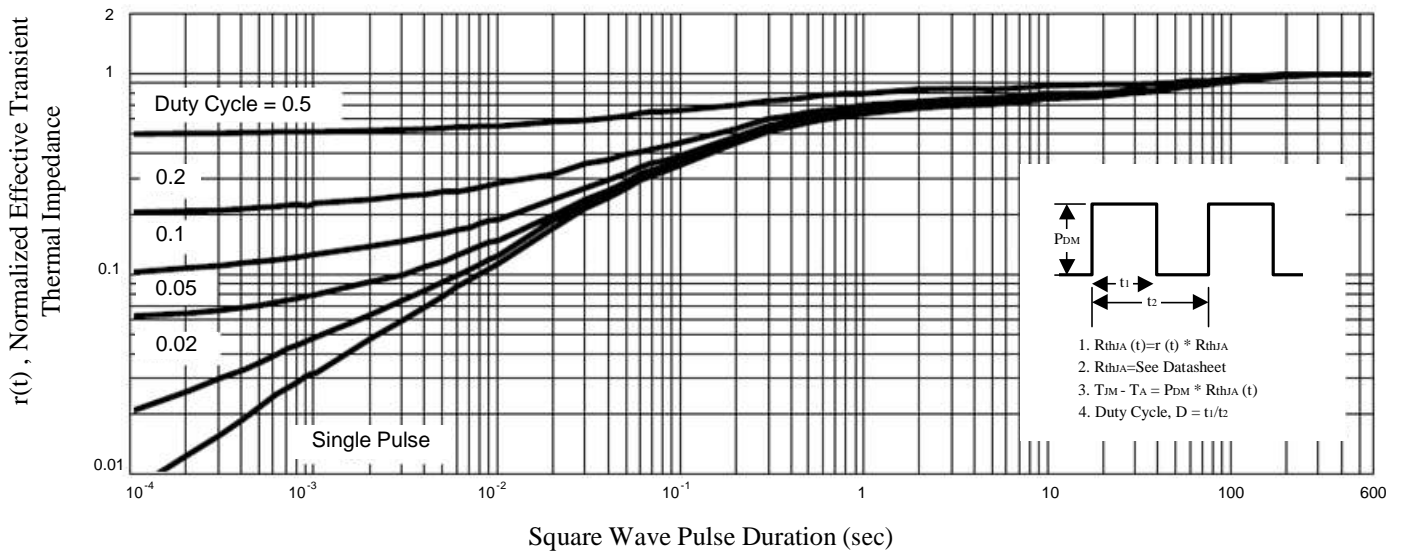


Figure 20. Normalized Thermal Transient Impedance Curve